Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/620,691	MIYATA ET AL.
Examiner	Art Unit
Long P. Nguyen	2616

SEARCHED			
Class	Subclass	Date	Examiner
370	352	5/29/2007	LN
370	356	5/29/2007	LN
370	389	5/29/2007	LN
370	351	5/29/2007	LN
370	385	5/29/2007	LN
379	142.02	5/29/2007	LN
709	240	5/29/2007	LN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEAR)
	DATE	EXMR
Consult with Ian Moore	5/29/2007	LN
Consult with Ahmad Matar	5/29/2007	LN
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